

Notic of R ferenc s Cited	Application/Control No. 09/785,416	Applicant(s)/Patent Under Reexamination TANAHASHI ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2002/0012816	01-2002	Shimizu et al.	428/694TM
	C	US-6387483	05-2002	Hokkyo et al.	428/332
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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